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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO	
10/696,588	10/30/2003	Michio Oryoji	032072	7203	
38834	7590 12/09/2005		EXAM	EXAMINER	
WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP 1250 CONNECTICUT AVENUE, NW			NGUYEN, HA T		
SUITE 700	CIICUI AVENUE, NW		ART UNIT	PAPER NUMBER	
WASHINGTON, DC 20036			2812	-	
			DATE MAILED: 12/09/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

Advisory Action Before the Filing of an Appeal Brief

Application No.	Applicant(s)	
10/696,588	ORYOJI, MICHIO	
Examiner	Art Unit	
Ha T. Nguyen	2812	

	Ha T. Nguyen	2812	
The MAILING DATE of this communication appe	ars on the cover sheet with the c	orrespondence add	ress
THE REPLY FILED 23 November 2005 FAILS TO PLACE THIS			
 The reply was filed after a final rejection, but prior to or on this application, applicant must timely file one of the follow places the application in condition for allowance; (2) a No a Request for Continued Examination (RCE) in compliance time periods: The period for reply expires 4 months from the mailing date 	ving replies: (1) an amendment, aff tice of Appeal (with appeal fee) in o e with 37 CFR 1.114. The reply mo of the final rejection.	fidavit, or other evider compliance with 37 Clust be filed within one	nce, which FR 41.31; or (3) of the following
b) The period for reply expires on: (1) the mailing date of this A no event, however, will the statutory period for reply expire to Examiner Note: If box 1 is checked, check either box (a) or (TWO MONTHS OF THE FINAL REJECTION. See MPEP 70	ater than SIX MONTHS from the mailing b). ONLY CHECK BOX (b) WHEN THE	g date of the final rejecti	on.
Extensions of time may be obtained under 37 CFR 1.136(a). The date have been filed is the date for purposes of determining the period of extender 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked. Any reply received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b) NOTICE OF APPEAL	tension and the corresponding amount shortened statutory period for reply origing than three months after the mailing da	of the fee. The appropri	ate extension fee ce action; or (2) as
 The Notice of Appeal was filed on A brief in comp filing the Notice of Appeal (37 CFR 41.37(a)), or any exter a Notice of Appeal has been filed, any reply must be filed 	nsion thereof (37 CFR 41.37(e)), to	avoid dismissal of th	ns of the date of e appeal. Since
AMENDMENTS		20 44 4 11	
3. The proposed amendment(s) filed after a final rejection, leading the proposed amendment (a) They raise new issues that would require further condition they raise the issue of new matter (see NOTE below). They are not deemed to place the application in beta appeal; and/or	nsideration and/or search (see NO w);	TE below);	
(d) They present additional claims without canceling a NOTE: (See 37 CFR 1.116 and 41.33(a)).	corresponding number of finally rej	ected claims.	
 4. The amendments are not in compliance with 37 CFR 1.12 5. Applicant's reply has overcome the following rejection(s) 6. Newly proposed or amended claim(s) would be all 	:		
non-allowable claim(s). 7. For purposes of appeal, the proposed amendment(s): a) how the new or amended claims would be rejected is provided the status of the claim(s) is (or will be) as follows: Claim(s) allowed: Claim(s) objected to: Claim(s) rejected: 1-21. Claim(s) withdrawn from consideration:		ll be entered and an e	explanation of
AFFIDAVIT OR OTHER EVIDENCE			
 The affidavit or other evidence filed after a final action, bu because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e). 	t before or on the date of filing a No d sufficient reasons why the affidav	otice of Appeal will <u>no</u> rit or other evidence is	t be entered necessary and
9. The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to o showing a good and sufficient reasons why it is necessary	vercome all rejections under appea	al and/or appellant fai	Is to provide a
 The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER 	n of the status of the claims after e	ntry is below or attach	ned.
 The request for reconsideration has been considered bu See attached. 	t does NOT place the application in	n condition for allowar	nce because:
12. Note the attached Information Disclosure Statement(s). Other:	PTO/SB/08 or PTO-1449) Paper N	lo(s)	
		H	1

Response to Applicant's arguments

1. Applicant's arguments' with regard to the rejections under 35 U.S.C. 102 or 103 have been fully considered, but they are not deemed to be persuasive for at least the following reasons.

Applicants argued that Watanabe et al. (USPN 6787907, hereinafter "Watanabe") does not teach the step of "etching the second interlayer insulating film again by using the hard mask as a mask" and the examiner's statement about the inherent masking function of the hard mask is not correct because Watanabe teaches that "the second interlayer insulating film is etched in some cases" does not teach inherency. This is true if one only reads this portion of the teaching, however if one considers the teaching as a whole and the example of the materials used, fluorine doped silicon oxide for first and second insulating layers 13 and 15, silicon nitride for first and second etch stopper layers 12, 14 and antireflection film, hard mask layer 16, then it is inherent that the hard mask layer 16 acts as a hard mask for the etching again of the second insulating layer because the selectivity between silicon nitride and silicon oxide is not so great that no portion of the second insulating layer is removed. If the layer does not act as a mask then the Fig. 1D would not have the shape as shown.

Applicant argued that Watanabe discloses that the upper surface of the filler 55 is lower than the upper surface of the second etch stop layer 14. This description opposes the invention. The examiner disagrees, as clearly shown in Fig. 17AB, the upper surface of the filler 55 is higher than the upper surface of the first insulating layer 13 while possibly lower than upper surface of the second etch layer 14.

Applicant also argued that Li does not disclose the missing features of APA because Li have the two etching steps performed without the step of photoresist removing. The examiner disagreed, the claims do not preclude the simultaneous etching of the second portion of the trench with the removal of the photoresist.

Therefore, the applied references do teach or make obvious all the limitations of the rejected claims 1-21. The final rejection should be sustained.

Conclusion

2. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Ha T. Nguyen whose telephone number is (571) 272-1678. The examiner can normally be reached on Monday-Friday from 8:30AM to 6:00PM, except the first Friday of each bi-week. The telephone number for Wednesday is (703) 560-0528.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Michael S. Lebentritt, can be reached on (571) 272-1873. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Ha Nguyen

Primary Examiner

12-07-05